



SHEET 1 OF 1

FORM PTO - 1449				ATTORNEY DOCKET NO.: DPL-043					
SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT				APPLICANT(S): Williams et al.					
				SERIAL NO.: 10/723,332					
				FILING DATE: November 26, 2003					
				CONFIRMATION NO: 9485					
				GROUP: 2859					
U.S. PATENT DOCUMENTS									
EXAM. INIT.		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE		
<i>W</i>	A21	4,561,286	12/31/85	Sekler et al.	73	23	6/28/84		
<i>W</i>	A22	5,476,002	12/19/95	Bowers et al.	73	24.01	5/5/94		
<i>W</i>	A23	6,370,955 B1	4/16/02	Tuller et al.	73	579	11/29/99		
FOREIGN PATENT DOCUMENTS									
EXAM. INIT.		DOCUMENT NUMBER	DATE	COUNTRY CODE	CLASS	SUB CLASS	FILING DATE	ABSTRACT ONLY	ENGLISH LANG (Y/N)
<i>W</i>	B1	1034475	6/29/66	GB			3/26/64	N	Y
<i>W</i>	B2	01/77624 A2	10/18/01	PCT			4/5/01	N	Y
OTHER ART, JOURNAL ARTICLES, ETC.									
EXAM. INIT.	OTHER DOCUMENTS: (Including Author, Title, Date, Relevant Pages, Place of Publication)								
<i>W</i>	E6	Copy of International Search Report, PCT/US 03/38300, Mailing Date May 27, 2004.							
EXAMINER <i>C. Velazquez</i>					DATE CONSIDERED <i>10/18/04</i>				

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FORM PTO - 107

INFORMATION DISCLOSURE STATEMENT

ATTORNEY DOCKET NO. DPL-043

APPLICANT(S): Williams et al.

APPLICATION NO. 10/723,332

FILING DATE: November 25, 2003 GROUP: 2859

U.S. PATENT DOCUMENTS

EXAM. INIT.		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>AC</i>	A1	4,783,174	11/08/88	Gmelin et al.	374	33	08/18/86
	A2	5,165,792	11/24/92	Crowe et al.	374	10	03/01/91
	A3	5,212,988	5/25/93	White et al.	73	599	10/10/91
	A4	5,288,147	02/22/94	Schaefer et al.	374	10	11/09/92
	A5	5,416,322	5/16/95	Chace et al.	250	288	04/21/94
	A6	5,842,788	12/01/98	Danley et al.	374	12	10/31/97
	A7	6,079,873	06/27/00	Cavicchi et al.	374	10	06/30/98
	A8	6,106,149	08/22/00	Smith	374	31	12/02/98
	A9	6,189,367	02/20/01	Smith et al.	73	19.03	12/02/98
	A10	6,190,035	02/20/01	Smith	374	31	05/26/00
	A11	6,238,085	05/29/01	Higashi et al.	374	10	12/31/98
	A12	6,354,732	03/12/02	Casati et al.	374	14	07/18/00
	A13	6,331,074	12/18/01	Kimura	374	10	01/16/98
	A14	6,370,939	04/16/02	Smith et al.	73	19.03	02/16/01
	A15	6,439,765	08/27/02	Smith	374	31	01/23/01
	A16	2001/0008081	07/19/01	Smith et al.	73	19.03	02/16/01
	A17	2001/0012312	08/09/01	Smith	374	31	01/23/01
	A18	2002/0003830	01/10/02	Tanaka et al.	374	31	01/12/01
	A19	2003/0043880	03/06/03	Meyler et al	374	32	06/28/02
<i>AC</i>	A20	2003/0033876	02/20/03	Roukes et al.	73	580	05/03/02

FOREIGN PATENT DOCUMENTS

[illegible]



SHEET 2 OF 2

FORM PTO - 1449		ATTORNEY DOCKET NO. DPL-043	
INFORMATION DISCLOSURE STATEMENT		APPLICANT(S): Williams et al.	
		APPLICATION NO. 10/723,332	
		FILING DATE: November 25, 2003 GROUP: Not yet assigned	
OTHER ART, JOURNAL ARTICLES, ETC.			
EXAM. INIT.	OTHER DOCUMENTS: (Including Author, Title, Date, Relevant Pages, Place of Publication)		
<i>cu</i>	C1	RJ LEE microsystems™, NanoScale 9100™ User's Manual. <i>no date</i>	
	C2	SAW Sensor Seminar, Helsinki University of Technology (HUT), Material Physics Lab (May 2002).	
	C3	TA Instruments "Modulated Thermogravimetric Analysis: A new approach for obtaining kinetic parameters." <i>no date</i>	
	C4	TA Instruments brochure TGA 2050 Thermogravimetric Analyzer. <i>no date</i>	
<i>cu</i>	C5	TA Instruments, "Thermogravimetric Analysis" (TGA)," slide presentation. <i>no date</i>	

*G. Verchick**10/18/04*